

[54] INSTRUMENT FOR DIAGONAL OBSERVATION BY MICROSCOPE

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[\*\*] Term: 14 Years

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[30] Foreign Application Priority Data

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[52] U.S. Cl. .... D16/131; D16/130

[58] Field of Search ..... D16/131, 130, 136, 134; 350/520, 511, 618, 519, 521-523, 414, 419

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[57] CLAIM

The ornamental design of an instrument for diagonal observation by microscope, as shown and described.

DESCRIPTION

FIG. 1 is a front elevational view of an instrument for diagonal observation by microscope showing my new design;

FIG. 2 is a rear elevational view thereof;

FIG. 3 is a top plan view thereof;

FIG. 4 is a bottom plan view thereof;

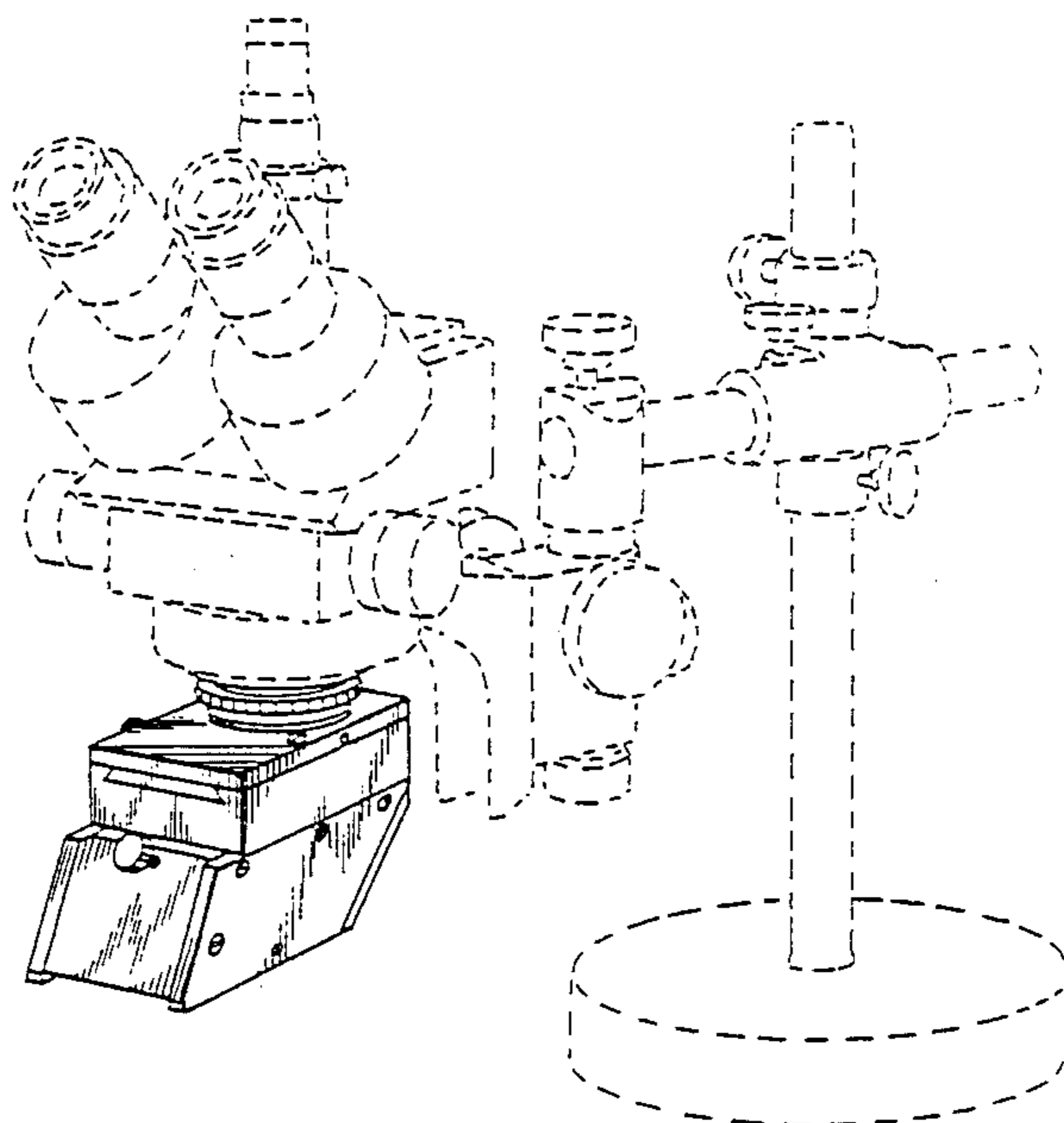
FIG. 5 is a left side elevational view thereof;

FIG. 6 is a right side elevational view thereof;

FIG. 7 is a sectional view taken along line VII—VII in FIG. 1;

FIG. 8 is a perspective view which illustrates the instrument mounted in association with a microscope, the latter being shown by broken lines for illustrative purposes only and forming no part of the claimed design; and

FIG. 9 is a right side elevational view similar to FIG. 6 illustrating a different operational state.



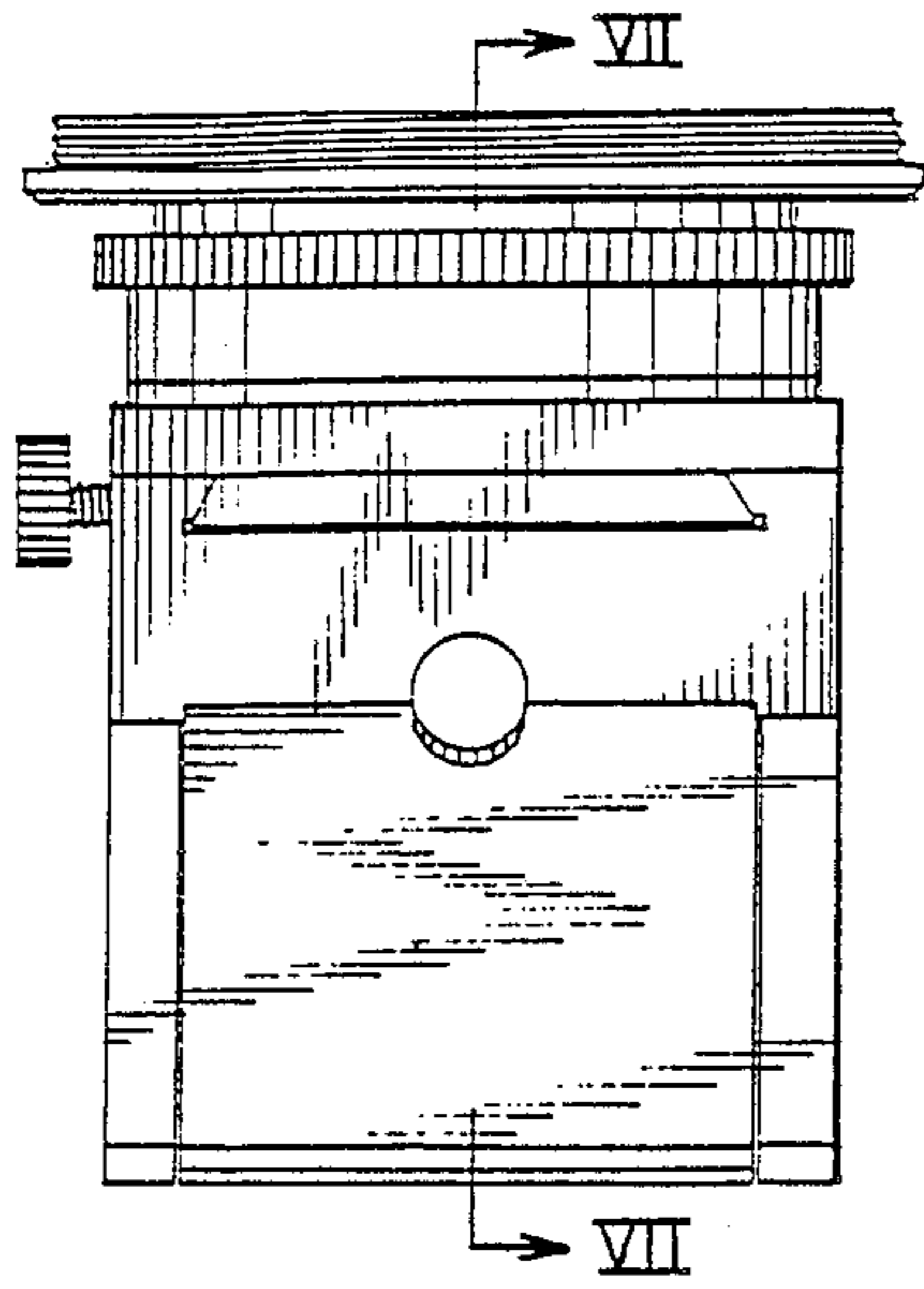


FIG. 1

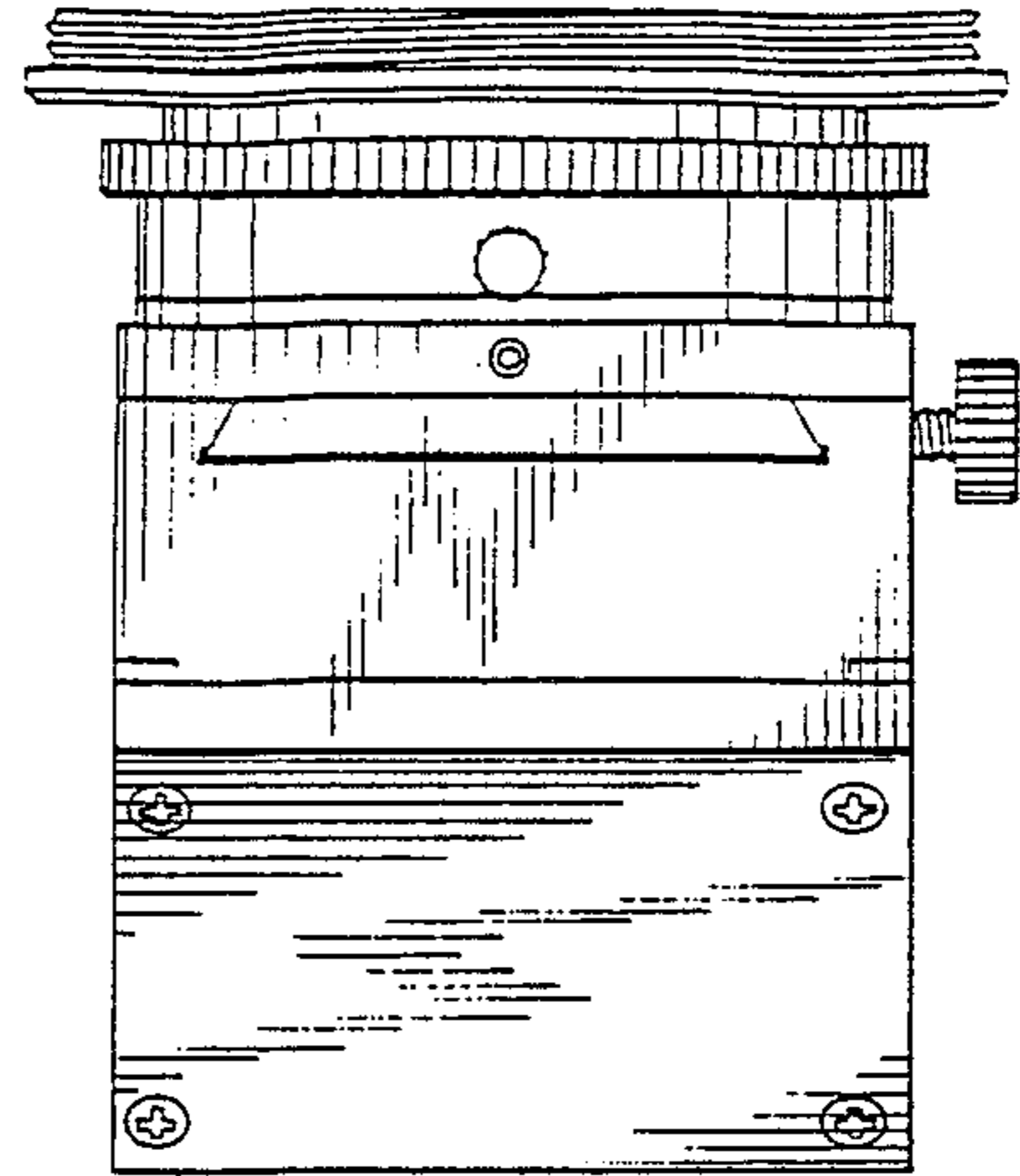


FIG. 2

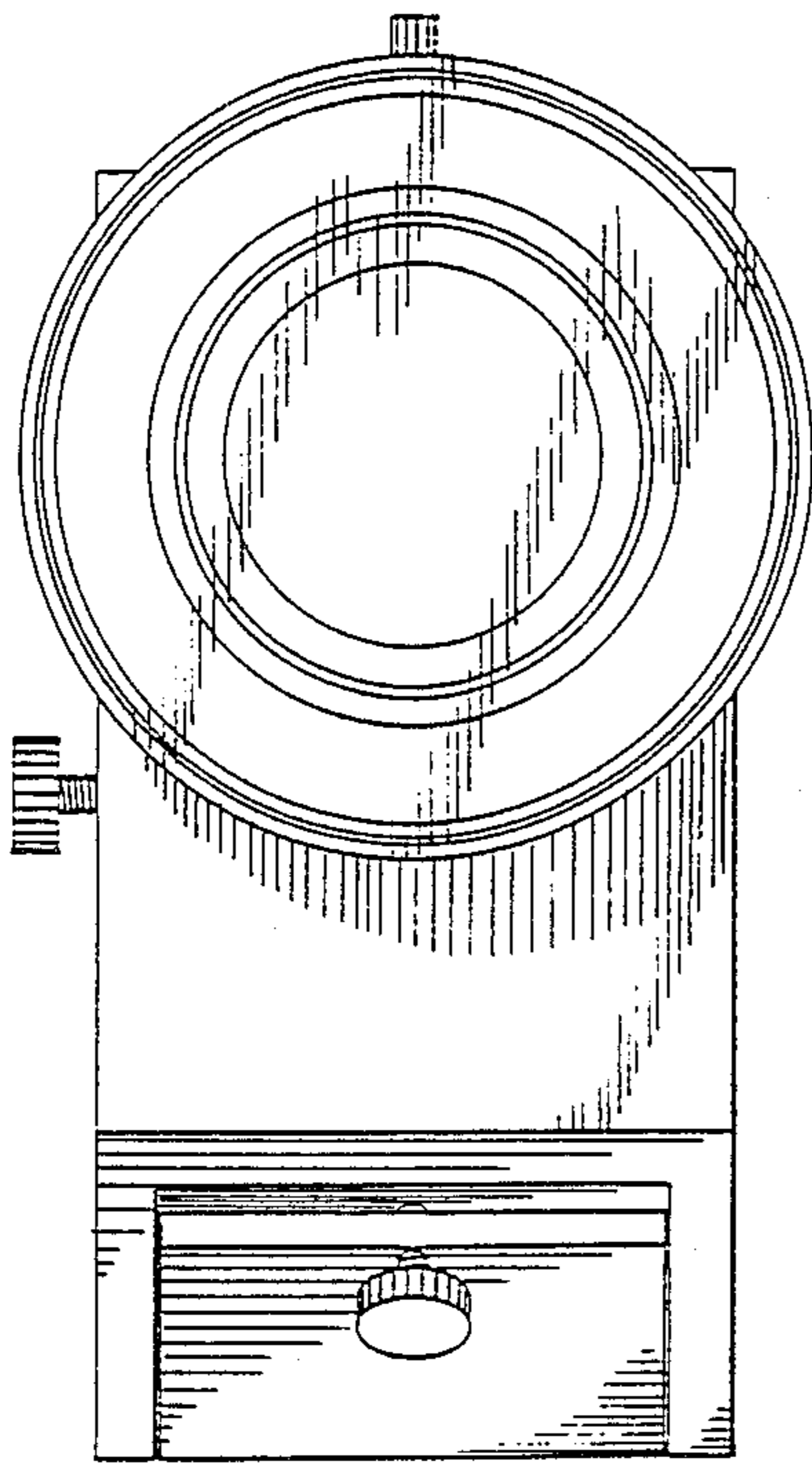


FIG. 3

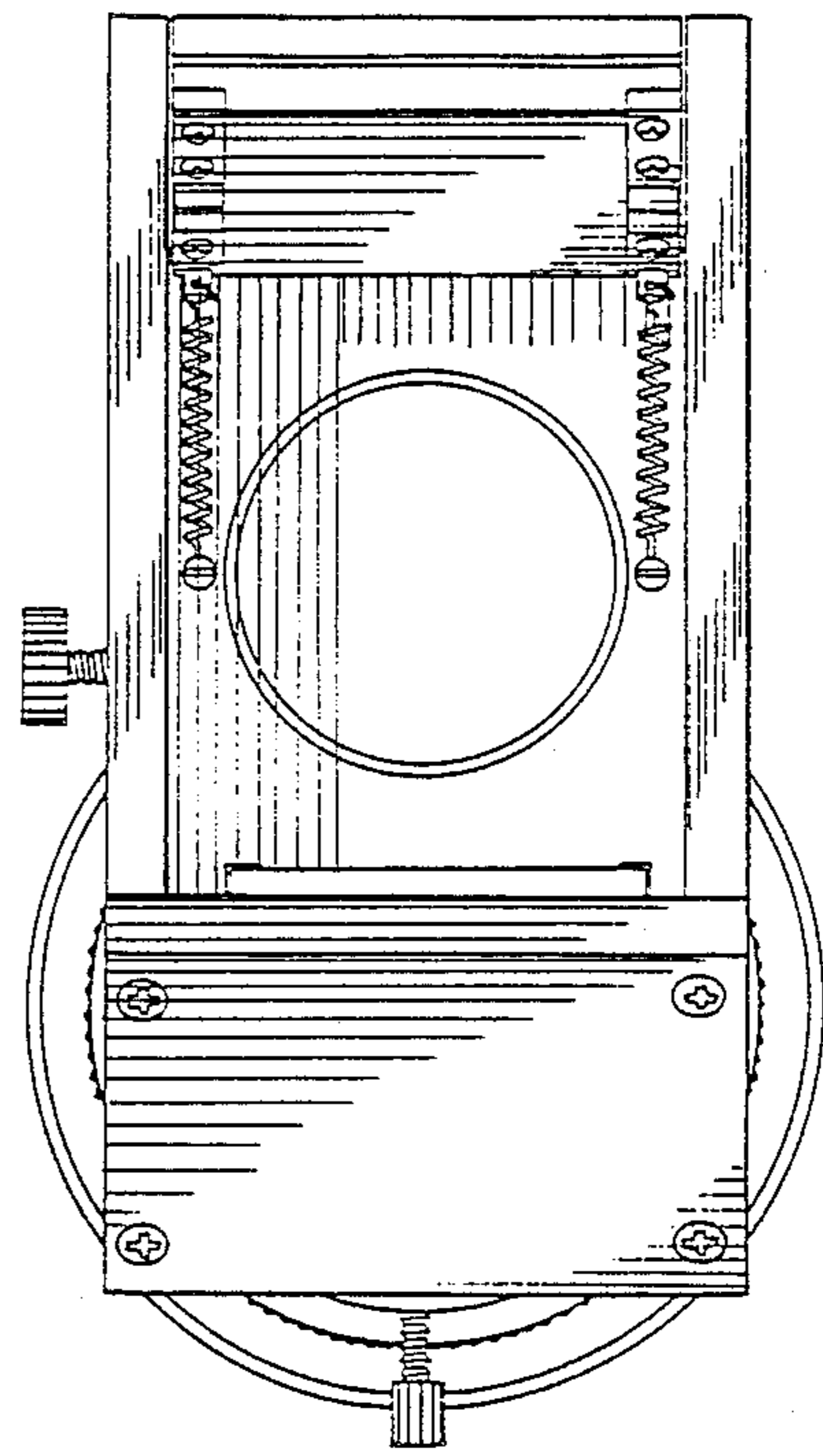


FIG. 4

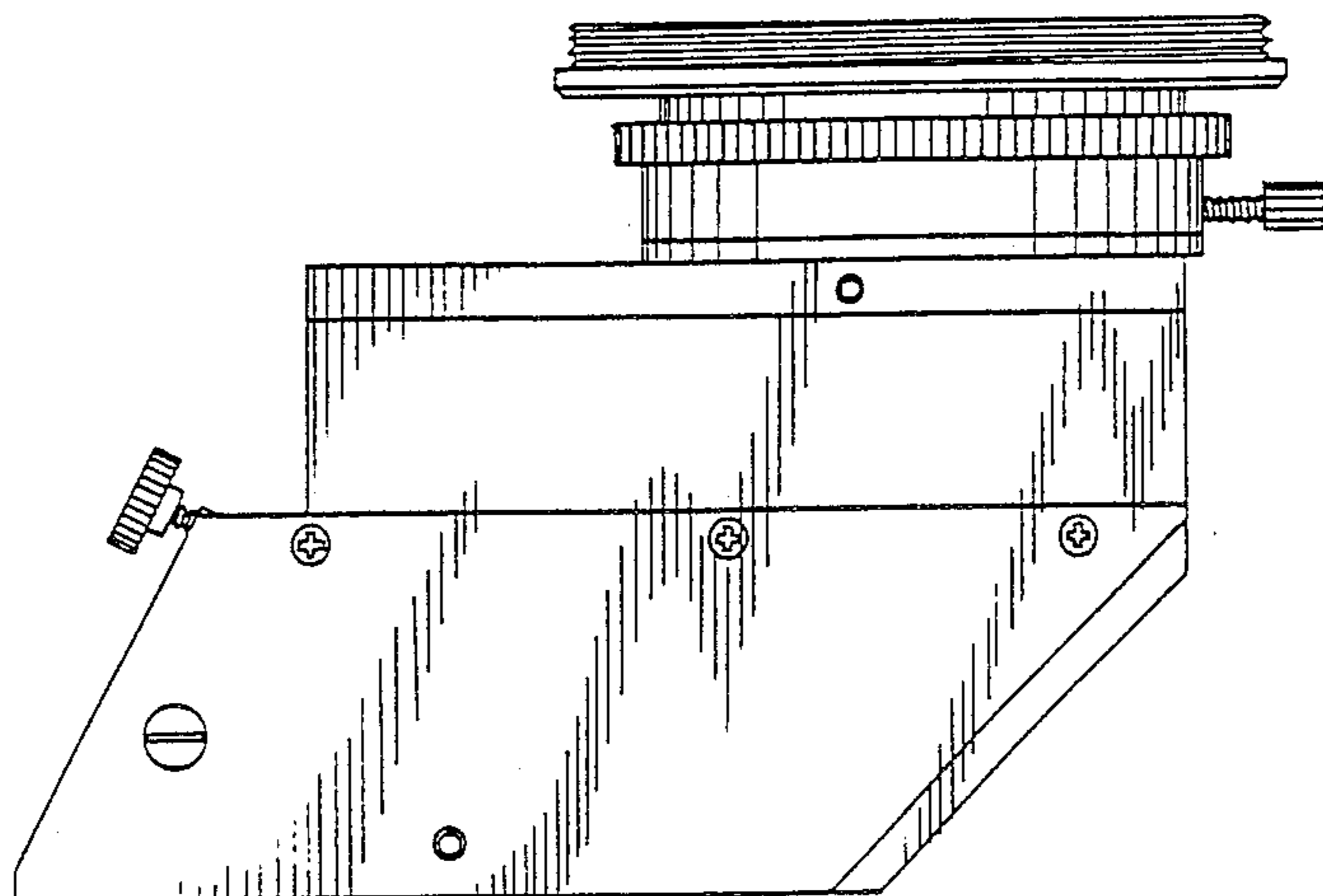


FIG. 6

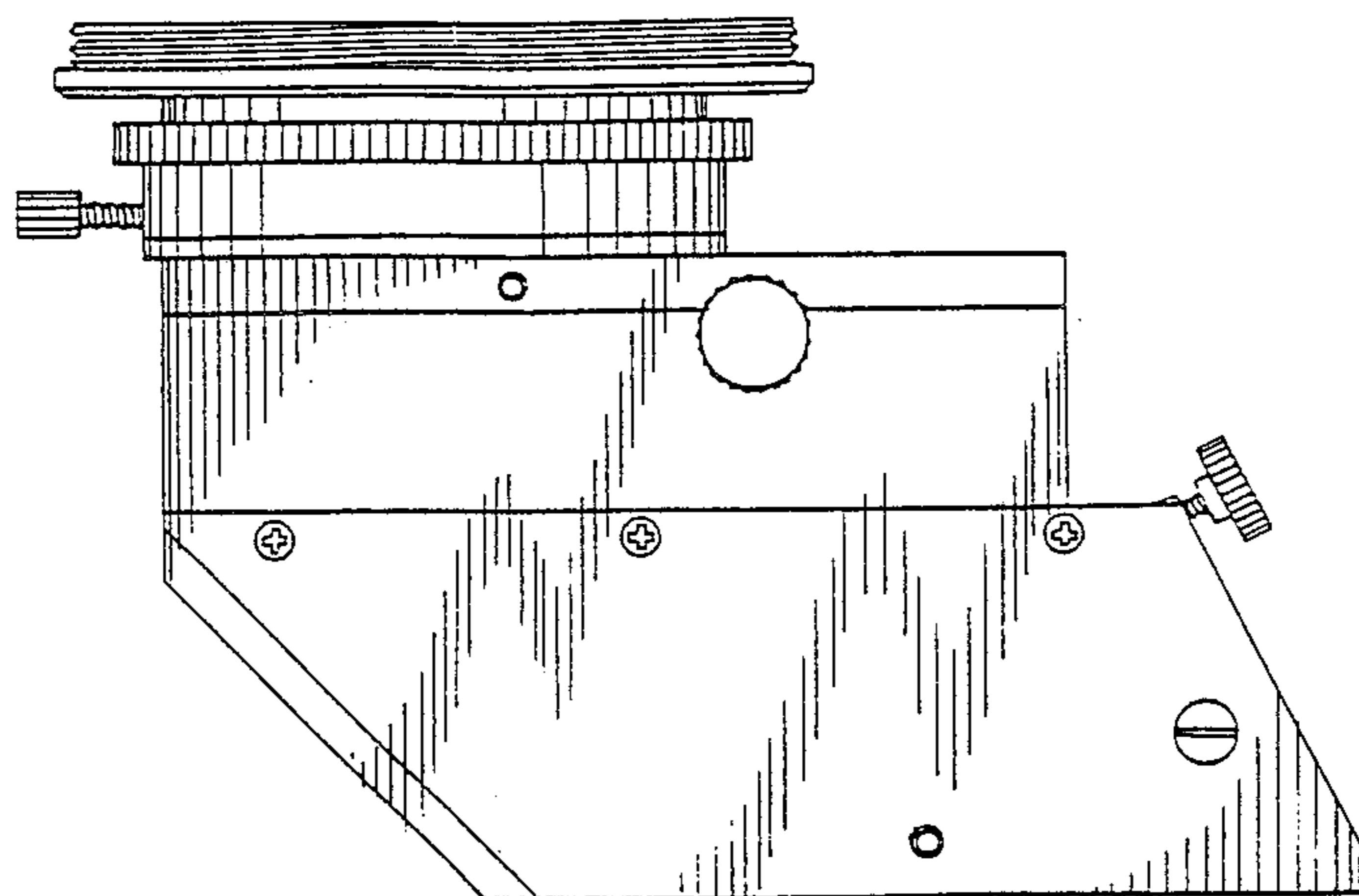


FIG. 5

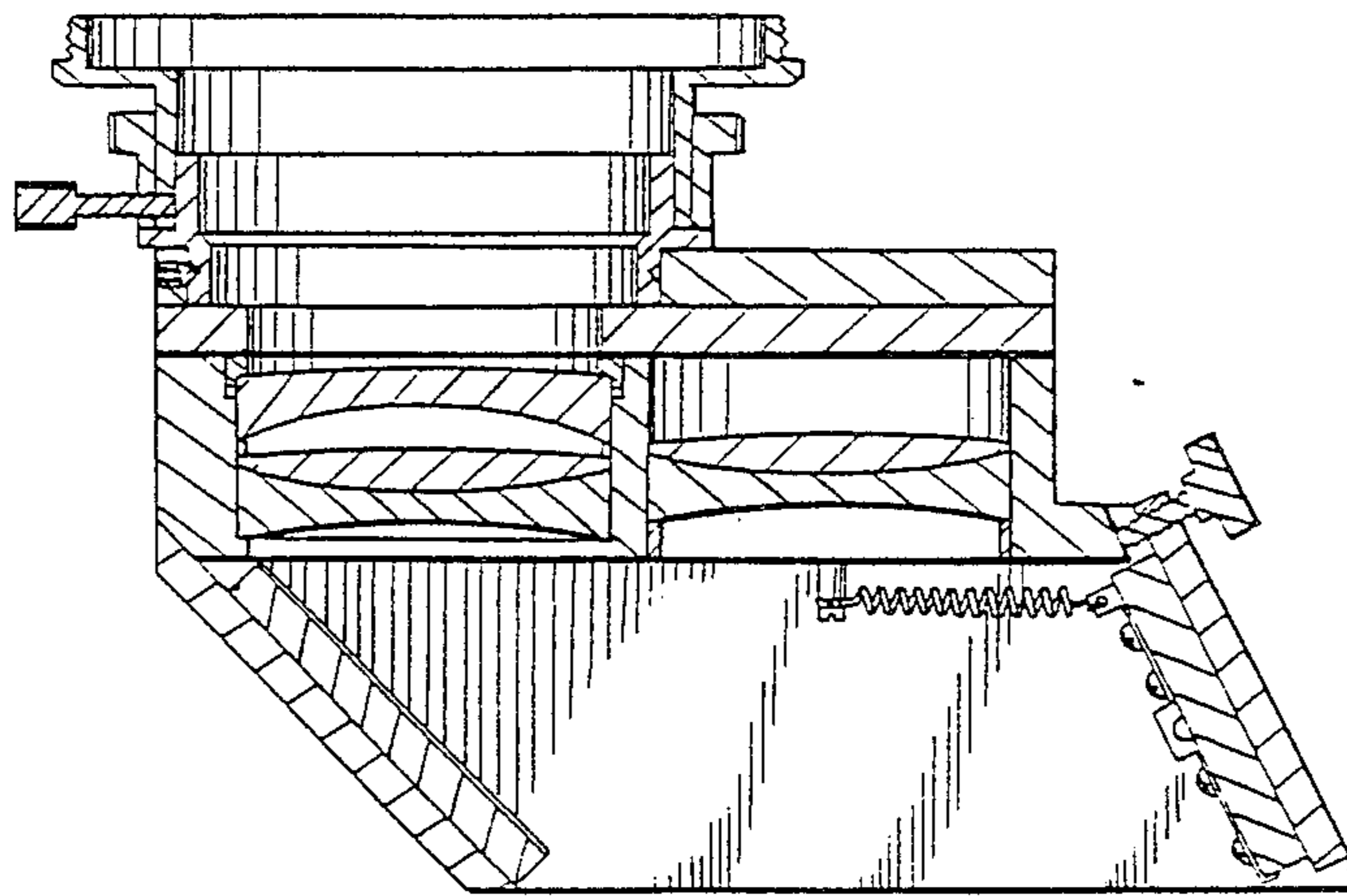


FIG. 7

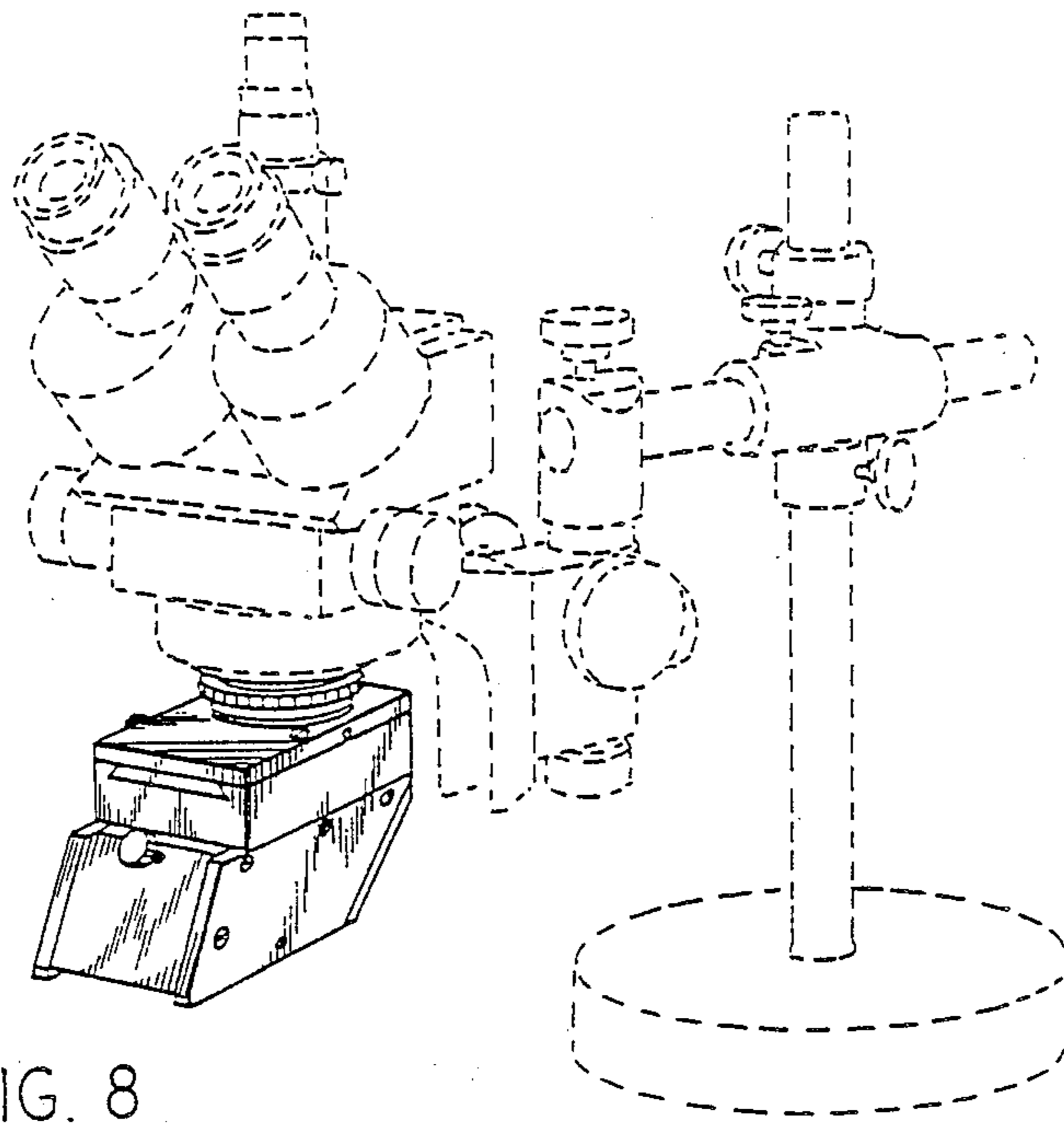


FIG. 8

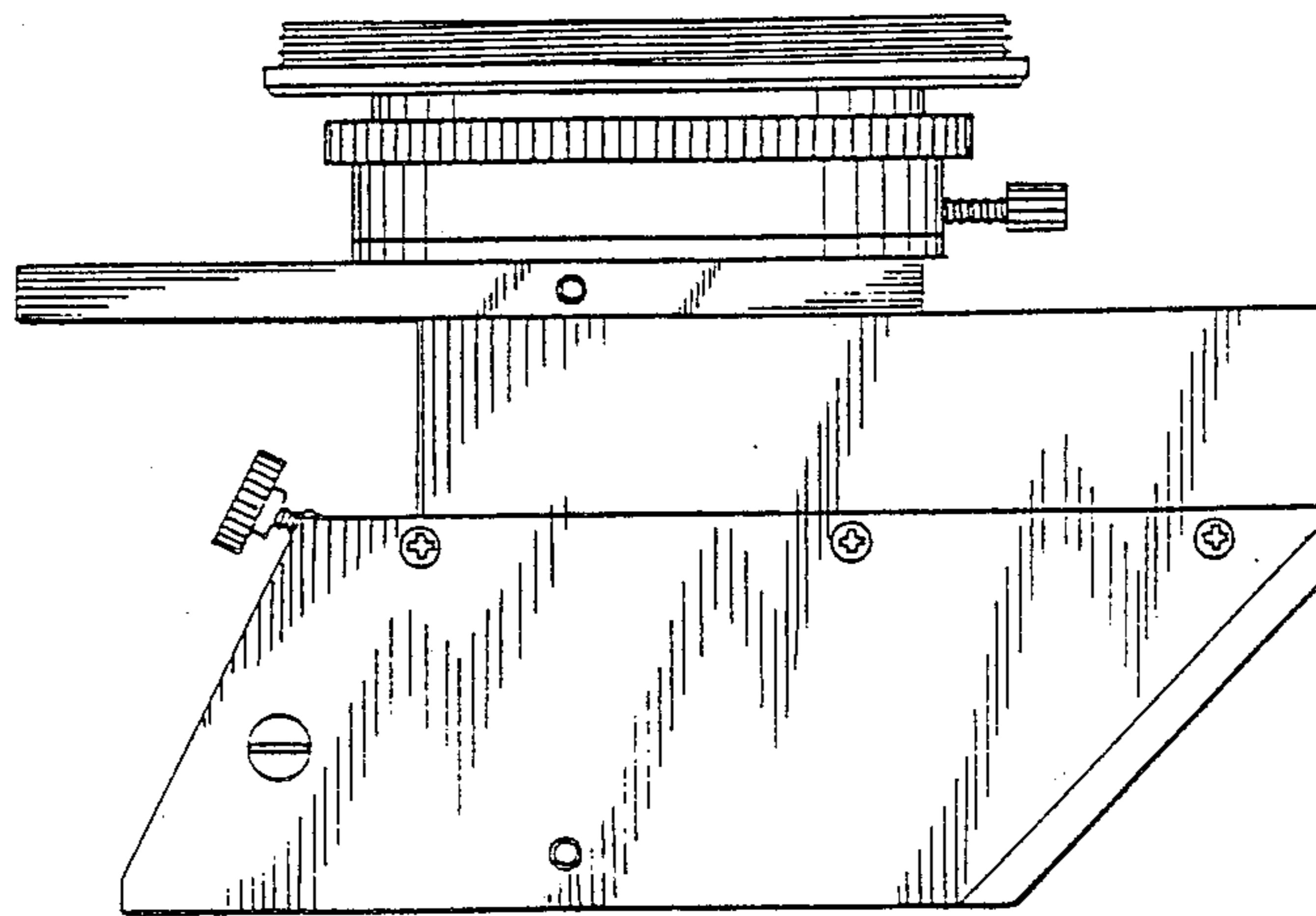


FIG. 9